Comparison of Non-Equilibrium Green's Function and Quantum-Corrected Monte Carlo Approaches in Nano MOS Simulation

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BACKGROUND

- Nano-scale MOSFETs with L_{ch} < 10nm have been realized in several research laboratories.
- A quantum mechanical modeling of nano-scale MOSFETs involving carrier's quasi-ballistic behaviors will be indispensable.
 - > Non-equilibrium Green's function approach (NEGF)
 - > Quantum-corrected Monte Carlo approach (QMC)

We present a joint study on comparison between the NEGF and QMC approaches for a nano-scale MOSFET.

Quantum-Corrected MC Approach

Transport equation with the lowest-order quantum correction

$$\frac{\partial f}{\partial t} + \sum_{i=x,y,z} \frac{\hbar k_i}{m_i^*} \frac{\partial f}{\partial r_i} - \frac{1}{\hbar} \nabla_{\mathbf{r}} U \cdot \nabla_{\mathbf{k}} f + \frac{1}{24\hbar} (\nabla_{\mathbf{r}} \cdot \nabla_{\mathbf{k}})^3 U f = \left(\frac{\partial f}{\partial t}\right)_C$$

Quantum-corrected Boltzmann transport equation

$$\frac{\partial f}{\partial t} + \sum_{i=x,y,z} \frac{\hbar k_i}{m_i^*} \frac{\partial f}{\partial r_i} - \frac{1}{\hbar} \nabla_{\mathbf{r}} \left(U + \underline{U}^{\mathrm{QC}} \right) \cdot \nabla_{\mathbf{k}} f = \left(\frac{\partial f}{\partial t} \right)_C$$

Quantum correction of potential

$$U^{\text{QC}}(\mathbf{r}) = -\frac{\hbar^2}{12m_x^*} \frac{\partial^2 \ln(n)}{\partial x^2} - \frac{\hbar^2}{12m_y^*} \frac{\partial^2 \ln(n)}{\partial y^2} - \frac{\hbar^2}{12m_z^*} \frac{\partial^2 \ln(n)}{\partial z^2}$$

Quantum-corrected equations of motion

$$\frac{d\mathbf{r}}{dt} = \mathbf{v} \quad , \quad \frac{d\mathbf{k}}{dt} = -\frac{1}{\hbar} \nabla_{\mathbf{r}} \left(U + U^{\text{QC}} \right)$$

Quantum-Corrected MC Simulation



Quasi-2D NEGF Approach

ID Schrödinger equation at each cross-section

$$\left[-\frac{\hbar^2}{2m_x^{\nu}}\frac{d}{dx}\left(\frac{1}{m_x^{\nu}}\frac{d}{dx}\right)+V(x,y)\right]\psi_n(x,y)=E_n(y)\psi_n(x,y)$$

ID Green's function equations along channel direction

$$\begin{bmatrix} E - \frac{\hbar^2 k_z^2}{2m_z^n} - \left(-\frac{\hbar^2}{2} \frac{d}{dy} \left(\frac{1}{m_y^n} \frac{d}{dy} \right) + E_n(y) \end{bmatrix} G_n^r(y, y', k_z, E) \\ -\int dy_1 \Sigma_n^r(y, y_1, k_z, E) G_n^r(y_1, y', k_z, E) = \delta(y - y') \\ \begin{bmatrix} E - \frac{\hbar^2 k_z^2}{2m_z^n} - \left(-\frac{\hbar^2}{2} \frac{d}{dy} \left(\frac{1}{m_y^n} \frac{d}{dy} \right) + E_n(y) \right) \end{bmatrix} G_n^{>,<}(y, y', k_z, E) \\ -\int dy_1 \Sigma_n^r(y, y_1, k_z, E) G_n^{>,<}(y_1, y', k_z, E) = \int dy \Sigma_n^{>,<}(y, y_1, k_z, E) G_n^{>,<}(y_1, y', k_z, E) \end{bmatrix}$$

Simulation Model



- Drain current as a function of right boundary of scattering, Y_{R-Scatt} is calculated.
- Only electron-phonon scattering is considered.
- Only the lowest quantized subbands for 2-fold and 4-fold valleys is considered in the NEGF method.
- Drain voltage is 0.6 V. Gate voltage is adjusted so that the injection electron density at the source edge of the channel becomes identical.

Drain Current vs Y_{R-Scatt}



There is a good agreement between the NEGF and QMC results, while the classical model underestimates the drain current.

Averaged Electron Velocity Profiles



Velocity (classical) < Velocity (quantum)

because an increase in the occupancy of the 2-fold valleys due to the energy quantizatization is not taken into account in the classical model.

Concentrations and Potentials



Influence of Impurity and Plasmon Scatterings



- Impurity scattering in source region
- plasmon scattering at drain-end of channel

are important to estimate drain current of MOSFET.

<u>SUMMARY</u>

- We have found that the non-equilibrium Green's function and quantum-corrected MC approaches are equivalent in the quantum transport simulation of nano-scale MOSFETs.
 - This result may be applicable to quantum correction models such as effective potential and Bohm potential, if the subband splitting is adequately incorporated.
- We have also demonstrated that the impurity scattering in the source region and the plasmon scattering at the drain-side of the channel are important to estimate the drain current accurately.